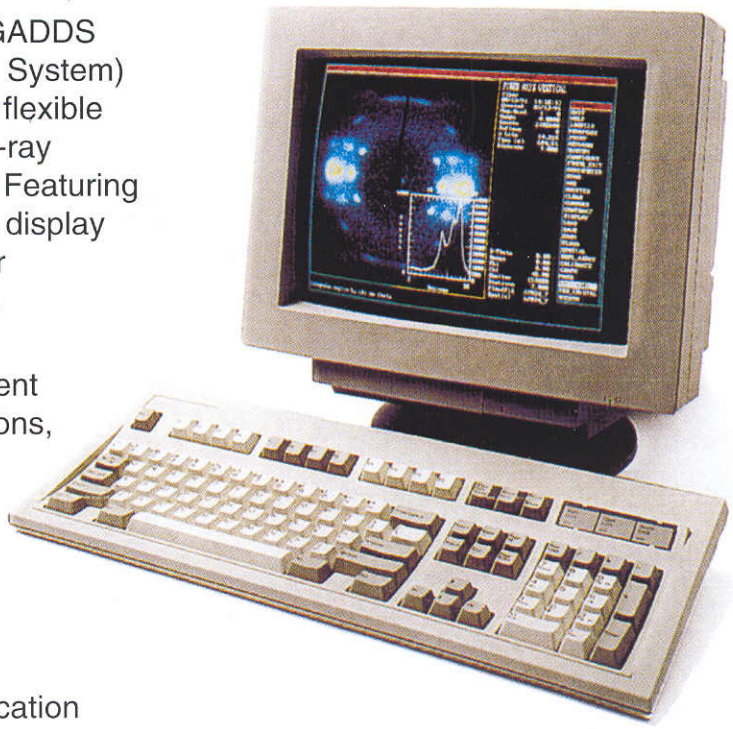
SIEMENS

Finally - an easy-to-use X-ray diffraction system for analyzing polymers

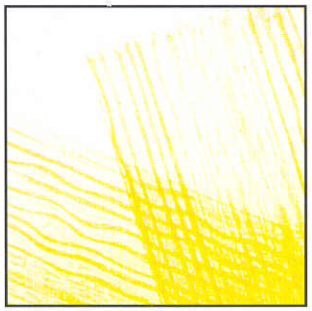
The Siemens Area Detector and GADDS (General Area Detector Diffraction System) polymer software are faster, more flexible and easier to run than ant other X-ray diffraction system available today. Featuring pop-up menus and real-time color display as part of a graphics-oriented user interface, the only thing missing is competition.

- Ideal for texture analysis, percent crystallinity and other applications, including QC
- Easily measures d-spacing, angles and intensities from any pixel location
- Versatile data files can be used with powder diffraction software and for phase identification and profile fitting

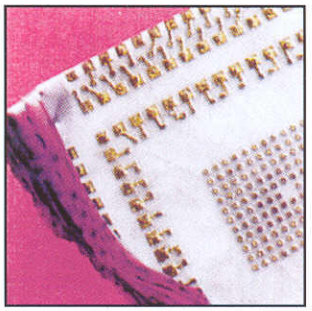


Plastics
True QC instrument for measuring intensities and d-spacings resulting from different draw rates or annealing temperatures

Texture
Measures scattering from amorphous through polycrystalline to 3-D single-crystalline with a powerful scripting feature



Composites
Versatile analysis of composite bondings with use of the system as an X-ray probe



In USA & Canada contact: Siemens Analytical X-ray Instruments, Inc • 6300 Enterprise Lane • Madison, WI 53719 • (608) 276-3000
Worldwide contact: Siemens AG, Analytical Systems AUT V 371 • P.O. Box 21 1262 • D 7500 Karlseruhe 21 • Germany • (0721) 595-4295

Produced by
CCLRC
Daresbury Laboratory
for CCP13

Useful World Wide Web addresses (URL)

CCP13 Home Page	http://www.dl.ac.uk/SRS/CCP13
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